

<b>Notice of References Cited</b>		Application/Control No. 10/597,853	Applicant(s)/Patent Under Reexamination ODAKA ET AL.	
		Examiner John P. Sheehan	Art Unit 1793	Page 1 of 1

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*	B	US-2006/0016515	01-2006	Tomizawa et al.	148/101
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	L	US-			
	M	US-			

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